

Search Notes

Application/Control No.

08/252,384

Examiner

Yong D. Pak

Applicant(s)/Patent under
Reexamination

MCDANIEL ET AL.

Art Unit

1652

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no:3, see SCORE	2/14/2008	YP
EAST (all databases): text and inventor search, see search history	2/14/2008	YP
PALM: search of all inventors	2/14/2008	YP